Application/Control No. Applicant(s)/Patent Under Reexamination 10/771,691 LIN, WEN CHIN ET AL. **Notice of References Cited** Examiner Art Unit Page 1 of 1 Andrew Q. Tran 2824 **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
Х	Α	US-6,256,224 B1	07-2001	Perner et al.	365/173
X	В	US-6,363,000 B2	03-2002	Perner et al.	365/66
X	С	US-6,584,006 B2	06-2003	Viehmann, Hans-Heinrich	365/97
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-	,		
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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	٧						
	w						
	x						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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